

FCC 47 CFR § 2.1091

RF EVALUATION REPORT (MPE)

FOR

GSM/WCDMA/LTE/5G NR Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax, NFC, WPT and UWB

MODEL NUMBER: SM-F956B/DS, SM-F956B

FCC ID: A3LSMF956B

REPORT NUMBER: 4791196626-S3V1

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Prepared for

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Testing Laboratory

TL-637

Revision History			
Rev.	Date	Revisions	Revised By
V1	5/2/2024	Initial Issue	--

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1. Attestation of SAR Characterization

Applicant Name	SAMSUNG ELECTRONICS CO.,LTD.
FCC ID	A3LSMF956B
Model Number	SM-F956B/DS, SM-F956B
Applicable Standards	FCC 47 CFR § 2.1091 KDB 680106 D01 RF Exposure Wireless Charging Apps
Date Tested	5/2/2024
Test Results	Pass
UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report. Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government	
Approved & Released By:	Prepared By:
	
Justin Park Operations Leader UL Korea, Ltd. Suwon Laboratory	Jeongyeon Won Laboratory Engineer UL Korea, Ltd. Suwon Laboratory

2. Test Methodology

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01.

3. Facilities and Accreditation

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro
☒ Shield Room 1

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at <https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf>.

4. Equipment Under Test

4.1 Description of EUT

The EUT has WPT (Wireless Power Transfer) feature which has inductive charging coil to charge phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum power consumption is 9.0 W in charging status.

4.2 WPT charging test considerations

Test configuration	Descriptions
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT (TA Charging from DUT)
DUT to Phone test configuration 3 (Cross position)	Charging from Phone to DUT
DUT to Phone test configuration 4 (Cross position)	Charging from Phone to DUT (TA Charging from DUT)
DUT to Watch test configuration 5	Charging from Watch to DUT
DUT to Watch test configuration 6	Charging from Watch to DUT (TA Charging from DUT)

Note:

- Configuration 2, 4 and 6 were tested with the worst case of configuration 1, 3 and 5.
- All test configurations considered for each Folder open and Folder close conditions.

4.3 KDB 680106 D01 EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device informations
(1) Power transfer frequency is less than 1 MHz	Yes. Operating Frequency is between 110kHz to 148 kHz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm or 20cm from the device are 21.20 % of the FCC H field limit.

4.4 Description of Test setup

SUPPORT EQUIPMENTS & PERIPHERALS

SUPPROT EQUIPMENT & PERIPHERALS LIST				
Description	Manufacturer	Model	Serial Numver	FCC ID
Phone	Samsung Electronics Co., Ltd.	SM-G986B/DS	R3CMB0C70XN	A3LSMG986B
Watch	Samsung Electronics Co., Ltd.	SM-R835F	RFAM90ZXFTF	A3LSMR835
Traver Adapter	Samsung Electronics Co., Ltd.	EP-TA800	R37N9BV0382HM3	DoC
USB Data Cable	Samsung Electronics Co., Ltd.	EP-DN980BBE	N/A	-

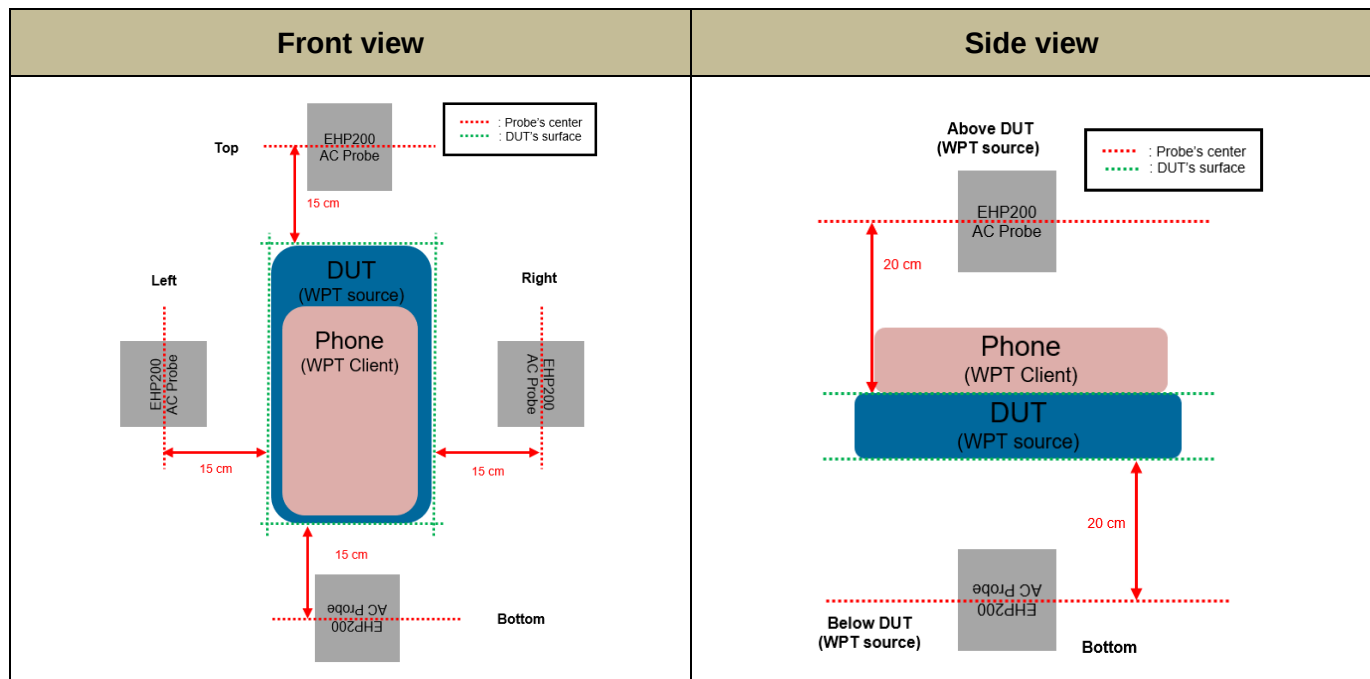
MEASUREMENT TEST SETUP

The measurement was taken using a probe placed 15 cm surrounding the device and 20 cm above the top surface of the EUT. Measurements were taken the top (charger below/above client) and all sides of the EUT per KDB680106 D01.

Charging test modes : The following three modes are tested in test configurations

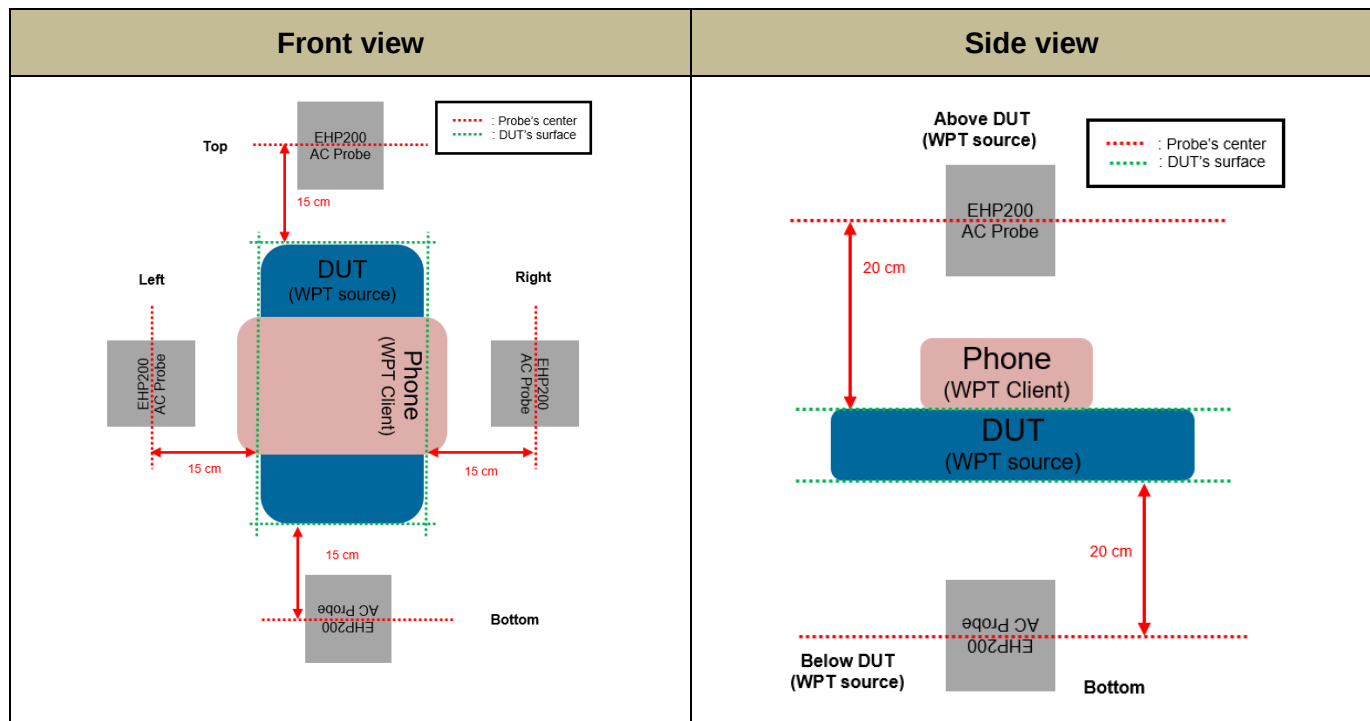
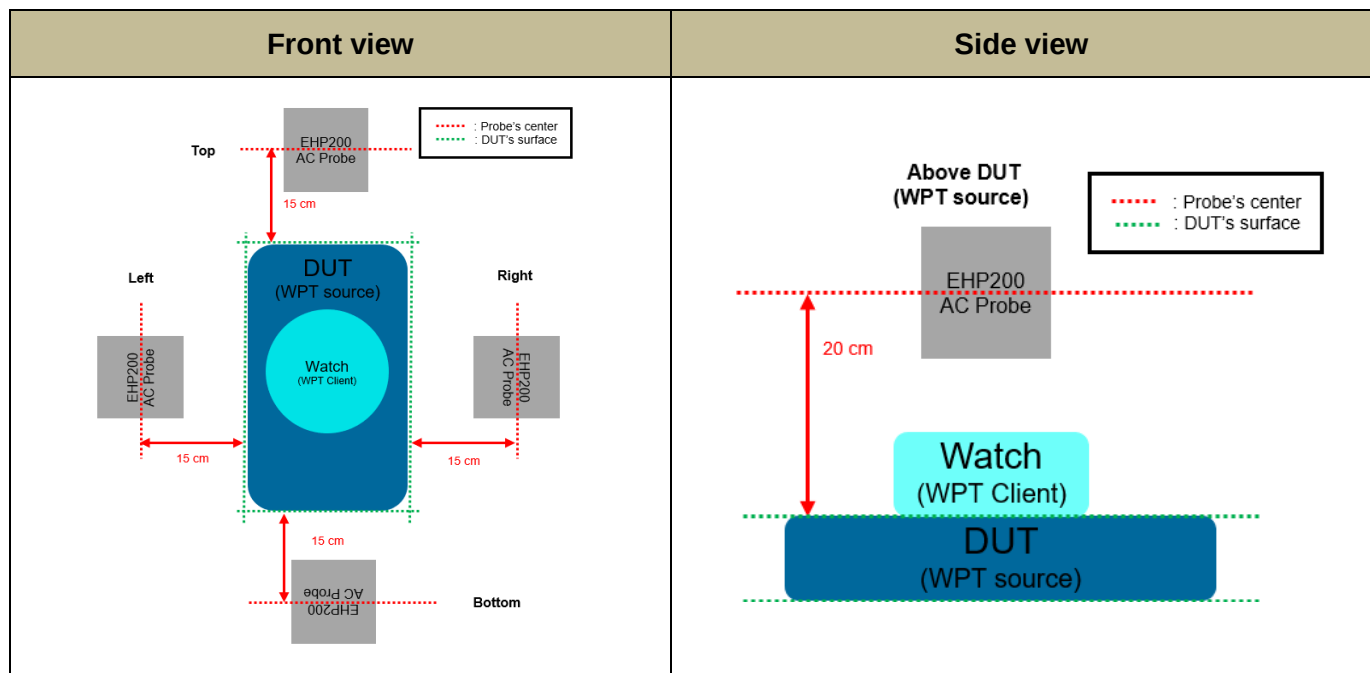
Mode
Operating (SUPPORT Equipment, <10% Power Charging)
Operating (SUPPORT Equipment, 50~55% Power Charging)
Operating (SUPPORT Equipment, 90~95% Power Charging)

DUT(Folder open/Folder Close) to phone test Configuration 1 & 2



Note:

Test distance is the distance between DUT's surface to center of probe.

DUT(Folder open/Folder Close) to phone test Configuration 3 & 4DUT(Folder open/Folder Close) to Watch test Configuration 5 & 6**Note:**

Test distance is the distance between DUT's surface to center of probe.

5. H-field Measurement equipment

The following equipment was used in this report;

Test equipment (Measurement probe)				
Description	Manufacturer	Model	S/N	Cal due.
E-H Field Analyzer	Narda	EHP-200AC	170WX91008	8-11-2024

6. Maximum Permissive Exposure test Results

6.1 FCC MPE Limits

§ 1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500			f/300	6
1500–100,000			5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500			f/1500	30
1500–100,000			1.0	30

f = frequency in MHz

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

6.2 MPE Test Results

H-Field Measurements

Peak measurement were performed. Additional test was performed in each Test mode by moving the probe surrounding the device to find the maximum exposure.

MPE(H-field) test Result

Folder Close condition

TEST results of DUT(Folder Close) to phone test Configuration 1 & 2

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 1	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.0392	1.63
			Below DUT	0.0314	
			Top	0.0851	
			Left	0.0449	
			Right	0.0422	
			Bottom	0.0351	
Configuration 1	Operating (WPT Client, 50-55 % Power Charging)		Top	0.0670	
Configuration 1	Operating (WPT Client, 90-95 % Power Charging)		Top	0.0798	
Configuration 2	Worst Charging test mode from Configuration 1		Top	0.0692	

TEST results of DUT(Folder Close) to phone test Configuration 3 & 4

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 3	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.1500	1.63
			Below DUT	0.0697	
			Top	0.1800	
			Left	0.3139	
			Right	0.2240	
			Bottom	0.0757	
Configuration 3	Operating (WPT Client, 50-55 % Power Charging)		Left	0.3092	
Configuration 3	Operating (WPT Client, 90-95 % Power Charging)		Left	0.3456	
Configuration 4	Worst Charging test mode from Configuration 3		Left	0.3015	

TEST results of DUT(Folder Close) to phone test Configuration 5 & 6

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 5	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.0734	1.63
			Top	0.0732	
			Left	0.0780	
			Right	0.0861	
			Bottom	0.0944	
Configuration 5	Operating (WPT Client, 50-55 % Power Charging)		Bottom	0.0911	
Configuration 5	Operating (WPT Client, 90-95 % Power Charging)		Bottom	0.0902	
Configuration 6	Worst Charging test mode from Configuration 5		Bottom	0.1087	

Folder Open condition**TEST results of DUT(Folder Open) to phone test Configuration 1 & 2**

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 1	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.0355	1.63
			Below DUT	0.0320	
			Top	0.0370	
			Left	0.0618	
			Right	0.0296	
			Bottom	0.0419	
Configuration 1	Operating (WPT Client, 50-55 % Power Charging)		Left	0.0549	
Configuration 1	Operating (WPT Client, 90-95 % Power Charging)		Left	0.0792	
Configuration 2	Worst Charging test mode from Configuration 1		Left	0.0762	

TEST results of DUT(Folder Open) to phone test Configuration 3 & 4

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 3	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.0522	1.63
			Below DUT	0.0647	
			Top	0.1267	
			Left	0.2492	
			Right	0.0392	
			Bottom	0.0374	
Configuration 3	Operating (WPT Client, 50-55 % Power Charging)		Left	0.1814	
Configuration 3	Operating (WPT Client, 90-95 % Power Charging)		Left	0.2085	
Configuration 4	Worst Charging test mode from Configuration 3		Left	0.2054	

TEST results of DUT(Folder Open) to phone test Configuration 5 & 6

Test configuration	Charging test mode	Test distance	Test positions	H-field meas H-field (A/m)	MPE (H-field) Limit (A/m)
Configuration 5	Operating (WPT Client, <10 % Power Charging)	20cm test distance for Above DUT/Below DUT & 15 cm test distance for Top/Left/Right/Bottom	Above DUT	0.0910	1.63
			Top	0.0745	
			Left	0.1565	
			Right	0.0364	
			Bottom	0.0611	
Configuration 5	Operating (WPT Client, 50-55 % Power Charging)		Left	0.1099	
Configuration 5	Operating (WPT Client, 90-95 % Power Charging)		Left	0.1319	
Configuration 6	Worst Charging test mode from Configuration 5		Left	0.1124	

6.2.1 Worst H-field result

H-Field Limit		
FCC RF Exposure	Maximum meas data (A/m)	Percentage (%)
1.63	0.3456	21.20

Conclusion:

H-Field result is less than 50% of the MPE limit.

Appendixes

Refer to separated files for the following appendixes.

4791196626-S3 FCC Report MPE_App A_Test setup photos

4791196626-S3 FCC Report MPE_App B_Probe Cal. Certificates

END OF REPORT